AUTOMATIC EXCHANGE OF DEGRADERS

IN ACCELERATED TESTING OF COMPUTER CHIPS

Abstract of the Disclosure

Issues that are addressed in accordance with at least one presently preferred

5   embodiment of the present invention, are: improvements upon the time it takes to

physically swap degraders (done previously by hand); the safety involved in doing so,

since the degraders become highly radioactive; possible improved energy resolution and

beam stability if the accelerator can be left running continuously; and in-situ monitoring

of beam current, beam position and stability. Particularly contemplated are methods and

10   arrangements for changing degraders automatically, not manually, and in a safe manner.